

### General Description

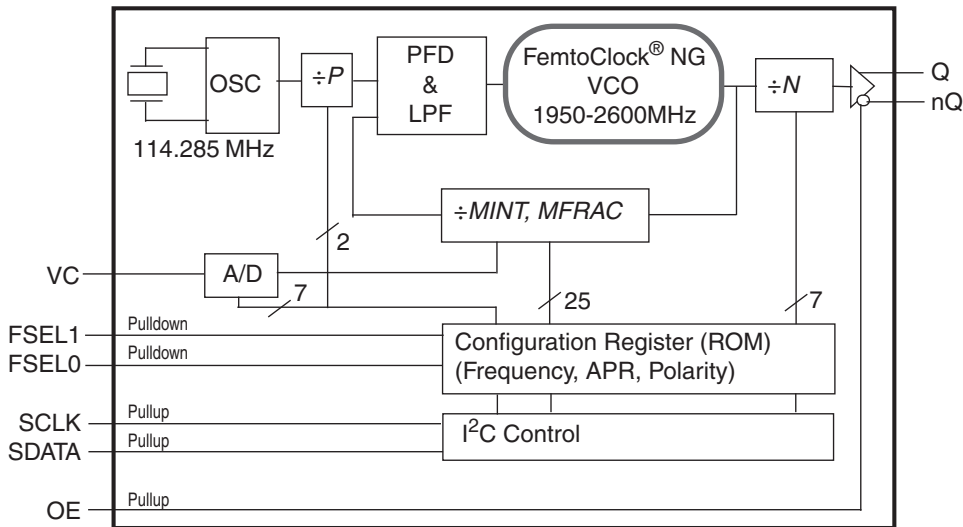
The IDT8N4QV01 is a Quad-Frequency Programmable VCXO with very flexible frequency and pull-range programming capabilities. The device uses IDT's fourth generation FemtoClock® NG technology for an optimum of high clock frequency and low phase noise performance. The device accepts 2.5V or 3.3V supply and is packaged in a small, lead-free (RoHS 6) 10-lead ceramic 5mm x 7mm x 1.55mm package.

Besides the 4 default power-up frequencies set by the FSEL0 and FSEL1 pins, the IDT8N4QV01 can be programmed via the I<sup>2</sup>C interface to any output clock frequency between 15.476MHz to 866.67MHz and from 975MHz to 1,300MHz to a very high degree of precision with a frequency step size of  $435.9\text{Hz} \div N$  ( $N$  is the PLL output divider). Since the FSEL0 and FSEL1 pins are mapped to 4 independent PLL, P, M and N divider registers (P, MINT, MFRAC and N), reprogramming those registers to other frequencies under control of FSEL0 and FSEL1 is supported. The extended temperature range supports wireless infrastructure, tele-communication and networking end equipment requirements.

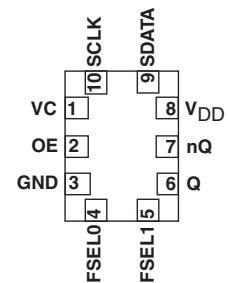
### Features

- Fourth generation FemtoClock® NG technology
- Programmable clock output frequency from 15.476MHz to 866.67MHz and from 975MHz to 1,300MHz
- Four power-up default frequencies (see part number order codes), re-programmable by I<sup>2</sup>C
- I<sup>2</sup>C programming interface for the output clock frequency, APR and internal PLL control registers
- Frequency programming resolution is  $435.9\text{Hz} \div N$
- Absolute pull-range (APR) programmable from  $\pm 4.5\text{ppm}$  to  $\pm 754.5\text{ppm}$
- One 2.5V or 3.3V LVDS differential clock output
- Two control inputs for the power-up default frequency
- LVCMOS/LVTTL compatible control inputs
- RMS phase jitter @ 156.25MHz (12kHz - 20MHz): 0.494ps (typical)
- RMS phase jitter @ 156.25MHz (1kHz - 40MHz): 0.594ps (typical)
- 2.5V or 3.3V supply voltage modes
- -40°C to 85°C ambient operating temperature
- Lead-free (RoHS 6) packaging

### Block Diagram



### Pin Assignment



**IDT8N4QV01 REV G DATA SHEET**  
**10-lead ceramic 5mm x 7mm x 1.55mm**  
**package body**  
**CD Package**  
**Top View**

**Table 1. Pin Descriptions**

Number	Name	Type		Description
1	VC	Input		VCXO Control Voltage. The control voltage versus frequency characteristics are set by the ADC_GAIN[5:0] register bits.
2	OE	Input	Pullup	Output enable pin. See Table 3B for function. LVCMOS/LVTTL interface levels.
3	GND	Power		Power supply ground.
4, 5	FSEL0, FSEL1	Input	Pulldown	Default frequency select pins. See Table 3A for function and Table 8 for the default frequency order codes. LVCMOS/LVTTL interface levels.
6, 7	Q, nQ	Output		Differential clock output. LVDS interface levels.
8	V <sub>DD</sub>	Power		Power supply pin.
9	SDATA	Input	Pullup	I <sup>2</sup> C Data Input. LVCMOS/LVTTL interface levels.
10	SCLK	Input	Pullup	I <sup>2</sup> C Clock Input. LVCMOS/LVTTL interface levels.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

**Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance	FSEL[1:0], SDATA, SCLK		5.5		pF
		VC		10		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			50		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			50		kΩ

## Function Tables

**Table 3A. Default Frequency Selection**

Input		Operation
FSEL1	FSEL0	
0 (default)	0 (default)	Default frequency 0
0	1	Default frequency 1
1	0	Default frequency 2
1	1	Default frequency 3

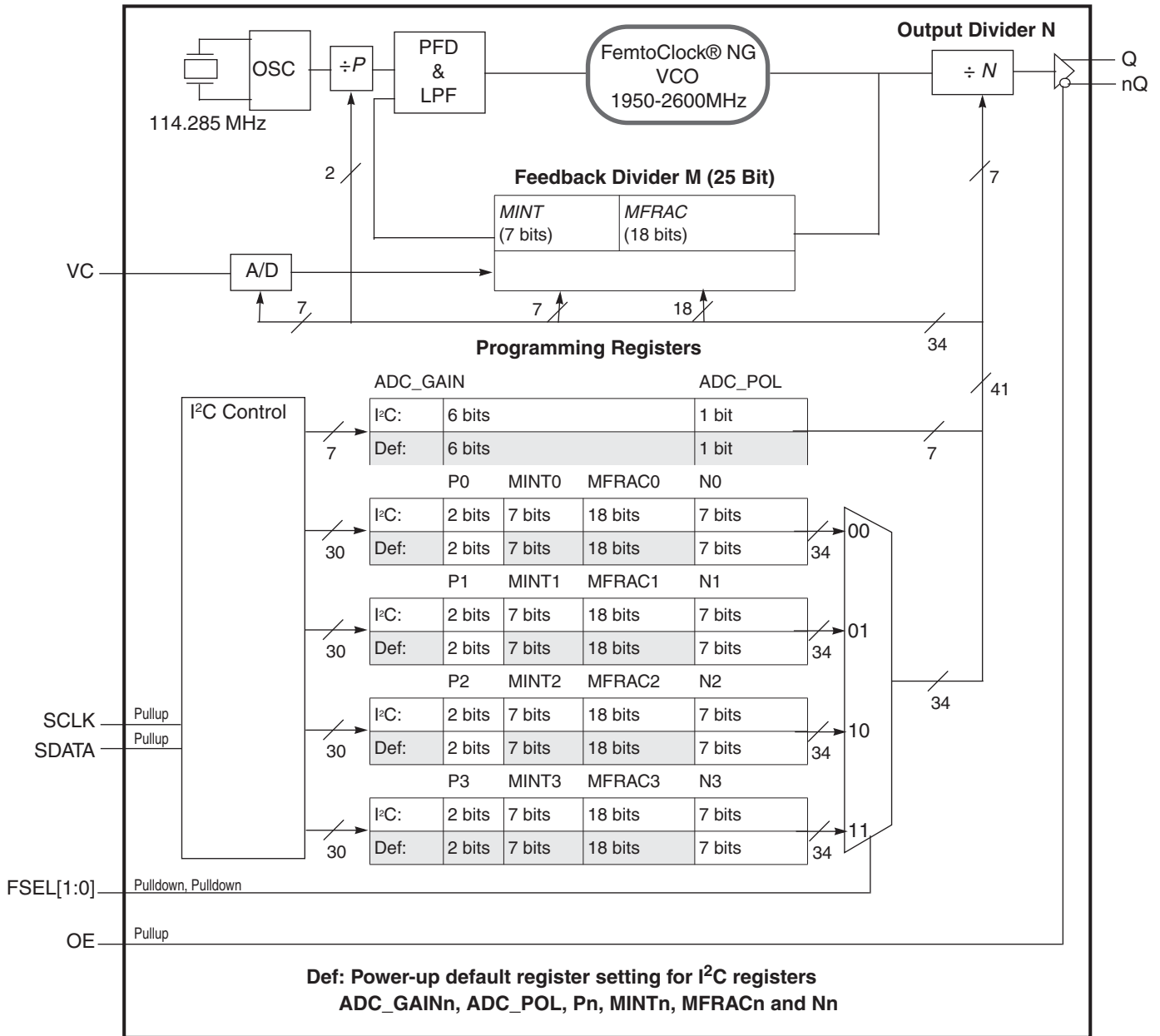
NOTE: The default frequency is the output frequency after power-up. One of four default frequencies is selected by FSEL[1:0]. See programming section for details.

**Table 3B. OE Configuration**

Input	Output Enable
OE	
0	Outputs Q, nQ are in high-impedance state.
1 (default)	Outputs are enabled.

NOTE: OE is an asynchronous control.

### Block Diagram with Programming Registers



## Principles of Operation

The block diagram consists of the internal 3<sup>rd</sup> overtone crystal and oscillator which provide the reference clock  $f_{XTAL}$  of either 114.285MHz or 100MHz. The PLL includes the FemtoClock NG VCO along with the Pre-divider ( $P$ ), the feedback divider ( $M$ ) and the post divider ( $N$ ). The  $P$ ,  $M$ , and  $N$  dividers determine the output frequency based on the  $f_{XTAL}$  reference and must be configured correctly for proper operation. The feedback divider is fractional supporting a huge number of output frequencies. The configuration of the feedback divider to integer-only values results in an improved output phase noise characteristics at the expense of the range of output frequencies. In addition, internal registers are used to hold up to four different factory pre-set  $P$ ,  $M$ , and  $N$  configuration settings. These default pre-sets are stored in the I<sup>2</sup>C registers at power-up. Each configuration is selected via the FSEL[1:0] pins and can be read back using the SCLK and SDATA pins.

The user may choose to operate the device at an output frequency different than that set by the factory. After power-up, the user may write new  $P$ ,  $N$  and  $M$  settings into one or more of the four configuration registers and then use the FSEL[1:0] pins to select the newly programmed configuration. Note that the I<sup>2</sup>C registers are volatile and a power supply cycle will reload the pre-set factory default conditions.

If the user does choose to write a different  $P$ ,  $M$ , and  $N$  configuration, it is recommended to write to a configuration which is not currently selected by FSEL[1:0] and then change to that configuration after the I<sup>2</sup>C transaction has completed. Changing the FSEL[1:0] controls results in an immediate change of the output frequency to the selected register values. The  $P$ ,  $M$ , and  $N$  frequency configurations support an output frequency range 15.476MHz to 866.67MHz and 975MHz to 1,300MHz.

The devices use the fractional feedback divider with a delta-sigma modulator for noise shaping and robust frequency synthesis capability. The relatively high reference frequency minimizes phase noise generated by frequency multiplication and allows more efficient shaping of noise by the delta-sigma modulator.

The output frequency is determined by the 2-bit pre-divider ( $P$ ), the feedback divider ( $M$ ) and the 7-bit post divider ( $N$ ). The feedback divider ( $M$ ) consists of both a 7-bit integer portion ( $MINT$ ) and an 18-bit fractional portion ( $MFRAC$ ) and provides the means for high-resolution frequency generation. The output frequency  $f_{OUT}$  is calculated by:

$$f_{OUT} = f_{XTAL} \cdot \frac{1}{P \cdot N} \cdot \left[ MINT + \frac{MFRAC + 0.5}{2^{18}} \right] \quad (1)$$

The four configuration registers for the  $P$ ,  $M$  ( $MINT$  &  $MFRAC$ ) and  $N$  dividers which are named  $P_n$ ,  $MINT_n$ ,  $MFRAC_n$  and  $N_n$  with  $n = 0$  to 3. “ $n$ ” denominates one of the four possible configurations.

As identified previously, the configurations of  $P$ ,  $M$  ( $MINT$  &  $MFRAC$ ) and  $N$  divider settings are stored the I<sup>2</sup>C register, and the configuration loaded at power-up is determined by the FSEL[1:0] pins.

**Table 4. Frequency Selection**

Input		Selects	Register
FSEL1	FSEL0		
0 (def.)	0 (def.)	Frequency 0	P0, MINT0, MFRAC0, N0
0	1	Frequency 1	P1, MINT1, MFRAC1, N1
1	0	Frequency 2	P2, MINT2, MFRAC2, N2
1	1	Frequency 3	P3, MINT3, MFRAC3, N3

## Frequency Configuration

An order code is assigned to each frequency configuration programmed by the factory (default frequencies). For more information on the available default frequencies and order codes, please see the Ordering Information Section in this document. For available order codes, see the *FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information* document.

For more information and guidelines on programming of the device for custom frequency configurations, the register description, the pull-range programming and the serial interface description, see the *FemtoClock NG Ceramic 5x7 Module Programming Guide*.

## Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, $V_{DD}$	3.63V
Inputs, $V_I$	-0.5V to $V_{DD} + 0.5V$
Outputs, $I_O$ (SDATA) Outputs, $I_O$ (LVDS) Continuous Current Surge Current	10mA 10mA 15mA
Package Thermal Impedance, $\theta_{JA}$	49.4°C/W (0 mps)
Storage Temperature, $T_{STG}$	-65°C to 150°C

## DC Electrical Characteristics

**Table 5A. Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Power Supply Voltage		3.135	3.3	3.465	V
$I_{DD}$	Power Supply Current				160	mA

**Table 5B. Power Supply DC Characteristics,  $V_{DD} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Power Supply Voltage		2.375	2.5	2.625	V
$I_{DD}$	Power Supply Current				155	mA

**Table 5C. LVCMOS/LVTTL DC Characteristic,  $V_{DD} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units	
$V_{IH}$	Input High Voltage	SEL [1:0], OE	$V_{CC} = 3.3V + 5\%$	1.7		$V_{CC} + 0.3$	V
		SEL [1:0], OE	$V_{CC} = 2.5V + 5\%$	1.7		$V_{CC} + 0.3$	V
$V_{IL}$	Input Low Voltage	SEL [1:0]	$V_{CC} = 3.3V + 5\%$	-0.3		0.5	V
		OE	$V_{CC} = 3.3V + 5\%$	-0.3		0.8	V
		SEL [1:0]	$V_{CC} = 2.5V + 5\%$	-0.3		0.5	V
		OE	$V_{CC} = 2.5V + 5\%$	-0.3		0.8	V
$I_{IH}$	Input High Current	OE				10	$\mu A$
		SDATA, SCLK	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$			5	$\mu A$
		FSEL0, FSEL1	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$			150	$\mu A$
$I_{IL}$	Input Low Current	OE		-500			$\mu A$
		SDATA, SCLK	$V_{DD} = 3.465V$ or $2.625V$ , $V_{IN} = 0V$	-150			$\mu A$
		FSEL0, FSEL1	$V_{DD} = 3.465V$ or $2.625V$ , $V_{IN} = 0V$	-5			$\mu A$

**Table 5D. LVDS DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{OD}$	Differential Output Voltage		247	350	454	mV
$\Delta V_{OD}$	$V_{OD}$ Magnitude Change				50	mV
$V_{OS}$	Offset Voltage		1.0	1.20	1.375	V
$\Delta V_{OS}$	$V_{OS}$ Magnitude Change				50	mV

## AC Electrical Characteristics

**Table 6A. VCXO Control Voltage Input ( $V_C$ ) Characteristics,  $V_{DD} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units	
$K_V$	Oscillator Gain, NOTE 1, 2, 3 $V_{DD} = 3.3V$	ADC_GAIN[5:0] = 000001		7.57		ppm/V	
		ADC_GAIN[5:0] = 000010		15.15		ppm/V	
		ADC_GAIN[5:0] = XXXXXX		$2 \cdot 12.5 \div V_{DD}$ ADC_GAIN		ppm/V	
		ADC_GAIN[5:0] = 111110		469.69		ppm/V	
		ADC_GAIN[5:0] = 111111		477.27		ppm/V	
	Oscillator Gain, NOTE 1, 2, 3 $V_{DD} = 2.5V$	ADC_GAIN[5:0] = 000001			10		ppm/V
		ADC_GAIN[5:0] = 000010			20		ppm/V
		ADC_GAIN[5:0] = XXXXXX			$2 \cdot 12.5 \div V_{DD}$ ADC_GAIN		ppm/V
		ADC_GAIN[5:0] = 111110			620		ppm/V
		ADC_GAIN[5:0] = 111111			630		ppm/V
$L_{VC}$	Control Voltage Linearity	BSL Variation; NOTE 4	-5	$\pm 1$	+5	%	
		Incremental; NOTE 5	-10	$\pm 5$	+10	%	
BW	Modulation Bandwidth			100		kHz	
$Z_{VC}$	VC Input Impedance			500		k $\Omega$	
$V_{C_{NOM}}$	Nominal Control Voltage			$V_{DD} \div 2$		V	
$V_C$	Control Voltage Tuning Range; NOTE 4		0		$V_{DD}$	V	

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1:  $V_C = 0V$  to  $V_{DD}$ .

NOTE 2: Nominal oscillator gain: Pull range divided by the control voltage tuning range of 3.3V.

E.g. for ADC\_GAIN[6:0] = 00.0001 the pull range is  $\pm 12.5\text{ppm}$ , resulting in an oscillator gain of  $2 * 12.5\text{ppm} \div 3.3V = 7.57\text{ppm/V}$ .

NOTE 3: For best phase noise performance, use the lowest  $K_V$  that meets the requirements of the application.

NOTE 4: BSL = Best Straight Line Fit: Variation of the output frequency vs. control voltage  $V_C$ , in percent.  $V_C$  ranges from 10% to 90%  $V_{DD}$ .

NOTE 5: Incremental slope is defined as the linearity in percent of the raw data (not relative to BSL) from 10% to 90%  $V_{DD}$ .



**Table 6B. AC Characteristics,  $V_{DD} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{OUT}$	Output Frequency Q, nQ	Output Divider, $N = 3$ to 126	15.476		866.67	MHz
		Output Divider, $N = 2$	975		1,300	MHz
$f_{VCO}$	VCO Frequency		1980		2600	MHz
$f_I$	Initial Accuracy	Measured at $25^\circ C$			$\pm 10$	ppm
$f_S$	Temperature Stability	Option code = A or B			$\pm 100$	ppm
		Option code = E or F			$\pm 50$	ppm
		Option code = K or L			$\pm 20$	ppm
$f_A$	Aging	Frequency drift over 10 year life			$\pm 3$	ppm
		Frequency drift over 15 year life			$\pm 5$	ppm
$f_T$	Total Stability	Option code A or B (10 year life)			$\pm 113$	ppm
		Option code E or F (10 year life)			$\pm 63$	ppm
		Option code K or L (10 year life)			$\pm 33$	ppm
$f_{jit(cc)}$	Cycle-to-Cycle Jitter; NOTE 1				20	ps
$f_{jit(per)}$	Period Jitter; NOTE 1			2.85	4	ps
$f_{jit}(\emptyset)$	RMS Phase Jitter (Random) Fractional PLL feedback and $f_{XTAL} = 114.285\text{MHz}$ (0xxx order codes)	$17\text{MHz} \leq f_{OUT} \leq 1300\text{MHz}$ , NOTE 2,3,4		0.475	0.990	ps
		$f_{OUT} = 156.25\text{MHz}$ , NOTE 2, 3, 4		0.494	0.757	ps
		$f_{OUT} = 156.25\text{MHz}$ , NOTE 2, 3, 5		0.594		ps
$\Phi_N(100)$	Single-side band phase noise, 100 Hz from Carrier	156.25MHz		-73.8		dBc/Hz
$\Phi_N(1k)$	Single-side band phase noise, 1kHz from Carrier	156.25MHz		-99.8		dBc/Hz
$\Phi_N(10k)$	Single-side band phase noise, 10kHz from Carrier	156.25MHz		-126.1		dBc/Hz
$\Phi_N(100k)$	Single-side band phase noise, 100kHz from Carrier	156.25MHz		-129.3		dBc/Hz
$\Phi_N(1M)$	Single-side band phase noise, 1MHz from Carrier	156.25MHz		-140.3		dBc/Hz
$\Phi_N(10M)$	Single-side band phase noise, 10MHz from Carrier	156.25MHz		-144.3		dBc/Hz
PSNR	Power Supply Noise Rejection	50mV Sinusoidal Noise 1kHz - 50MHz		-54		db
$t_R / t_F$	Output Rise/Fall Time	20% to 80%	100		425	ps
odc	Output Duty Cycle		45		55	%
$t_{OSC}$	Oscillator Start-Up Time				20	ms
$t_{SET}$	Output Frequency Settling Time after FSEL0 and FSEL1 Values are Changed			470		$\mu s$

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions. All AC parameters are characterized with P=1 and pull range  $\pm 250$  ppm.

NOTE: XTAL parameters (initial accuracy, temperature stability, aging and total stability) are guaranteed by manufacturing.

NOTE 1: This parameter is defined in accordance with JEDEC standard 65.

NOTE 2: Please refer to the phase noise plots.

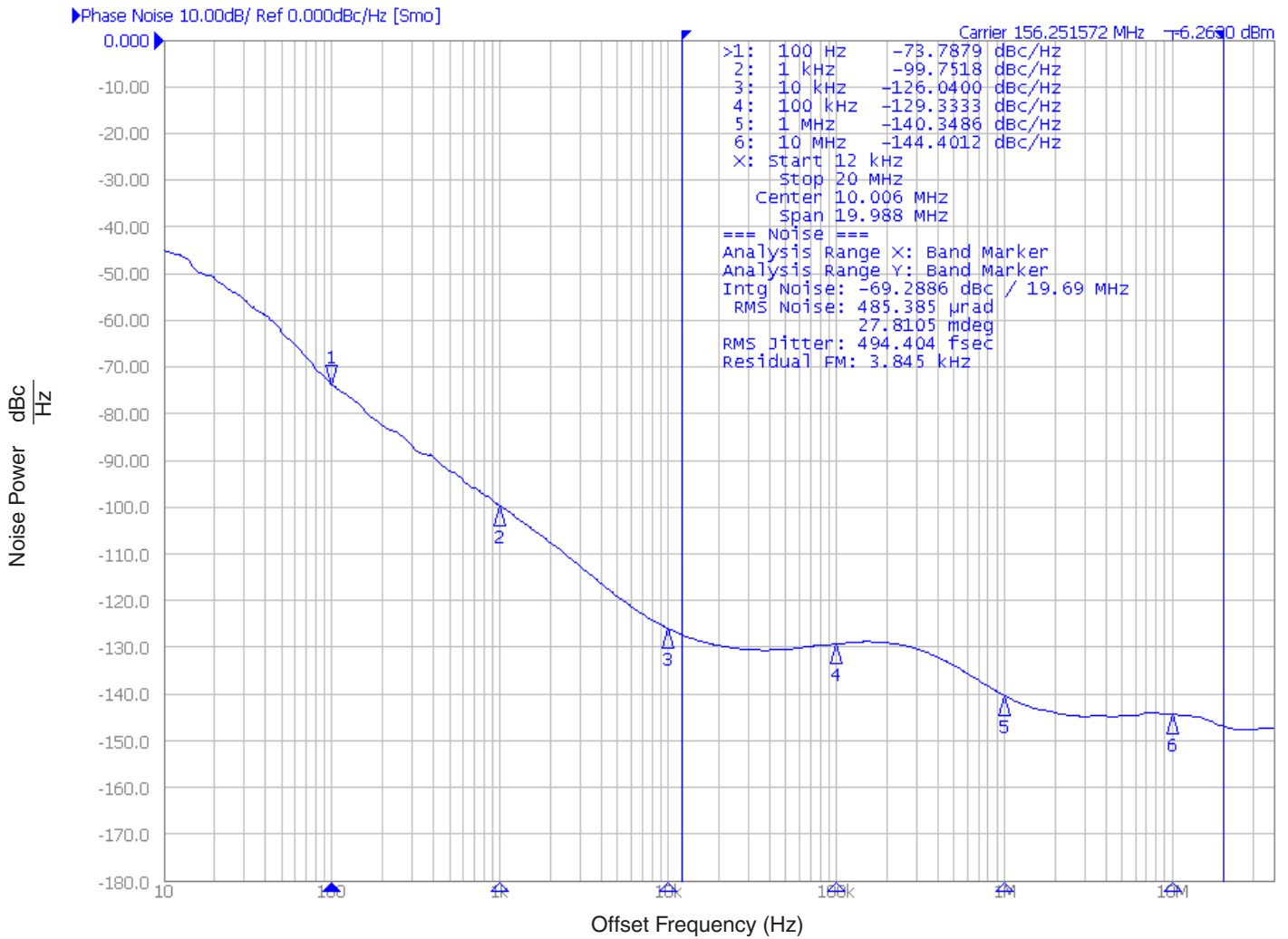
NOTES continued on next page.

NOTE 3: Please see the FemtoClock NG Ceramic 5x7 Modules Programming guide for more information on finding the optimum configuration for phase noise.

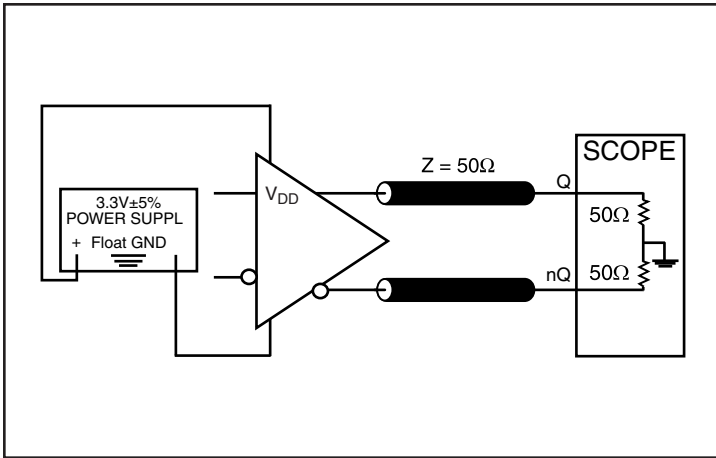
NOTE 4: Integration range: 12kHz-20MHz.

NOTE 5: Integration range: 1kHz-40MHz.

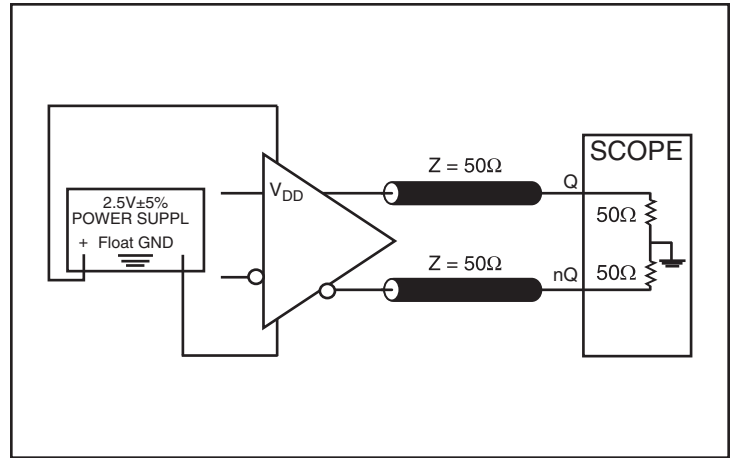
### Typical Phase Noise at 156.25MHz (12kHz - 20MHz)



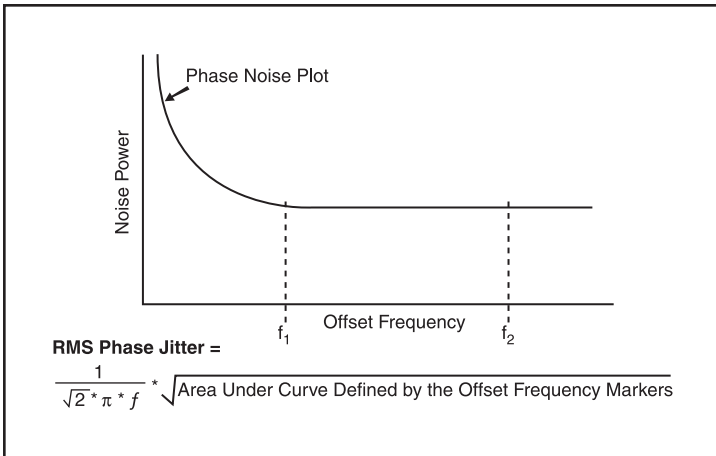
### Parameter Measurement Information



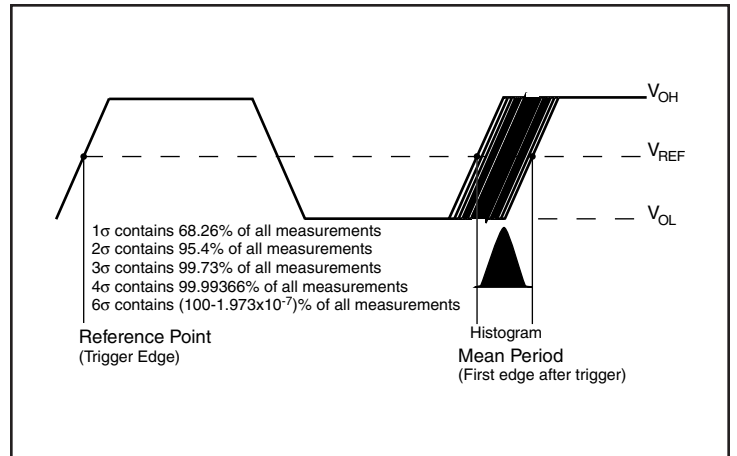
3.3V LVDS Output Load AC Test Circuit



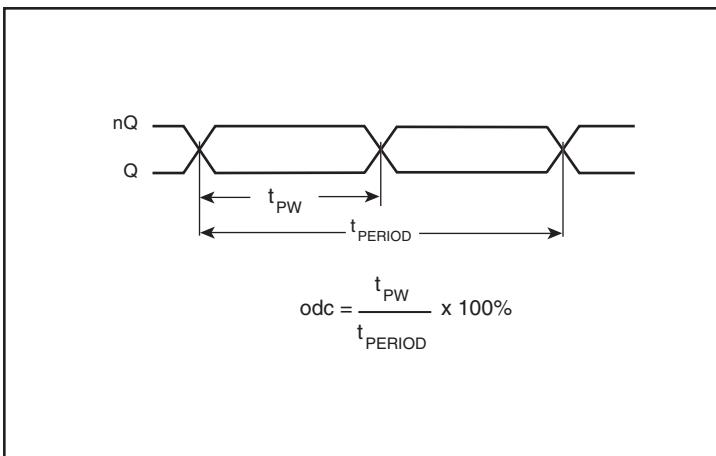
2.5V LVDS Output Load AC Test Circuit



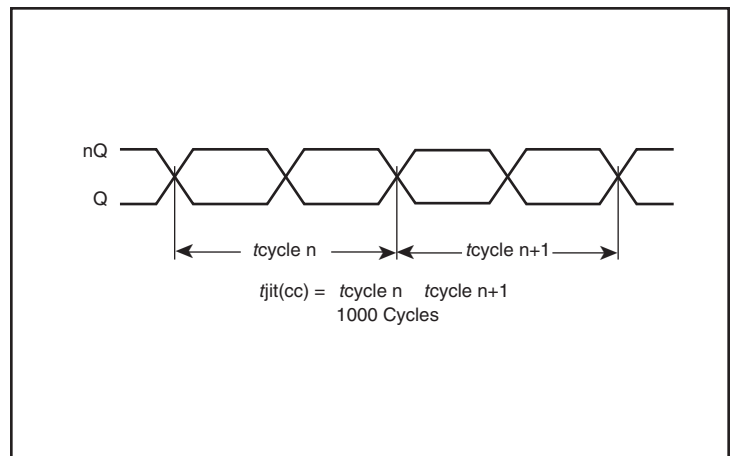
RMS Phase Jitter



Period Jitter

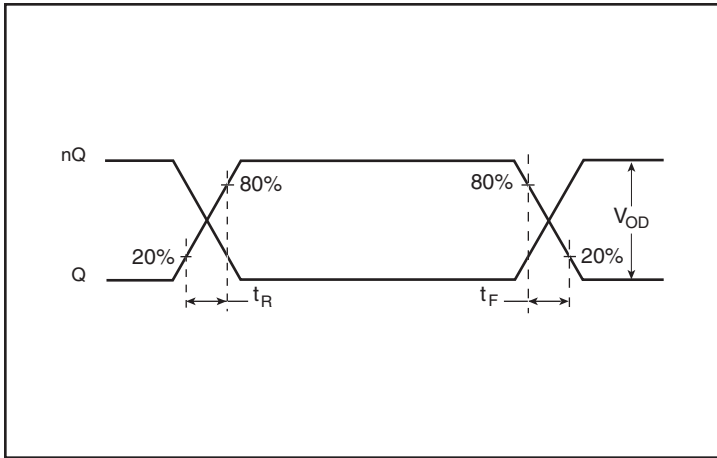


Output Duty Cycle/Pulse Width/Period

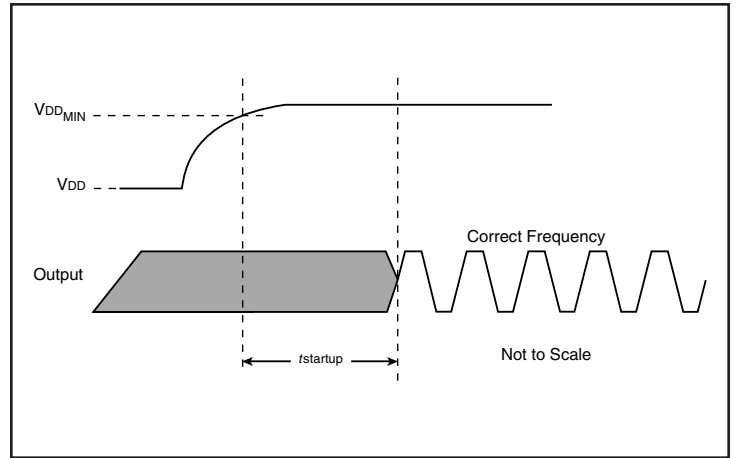


Cycle-to-Cycle Jitter

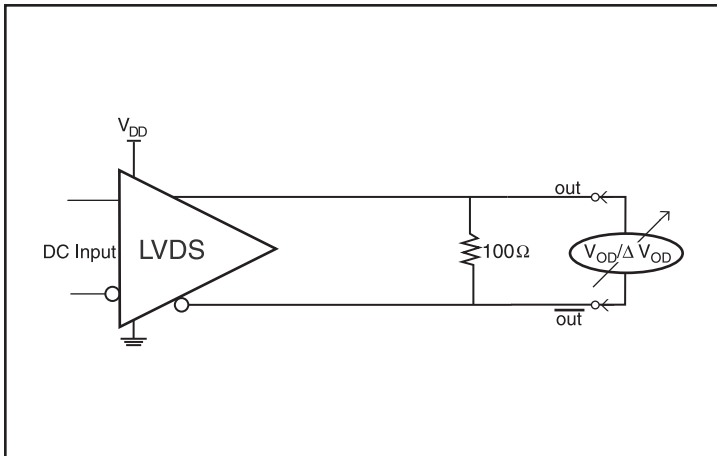
### Parameter Measurement Information (continued)



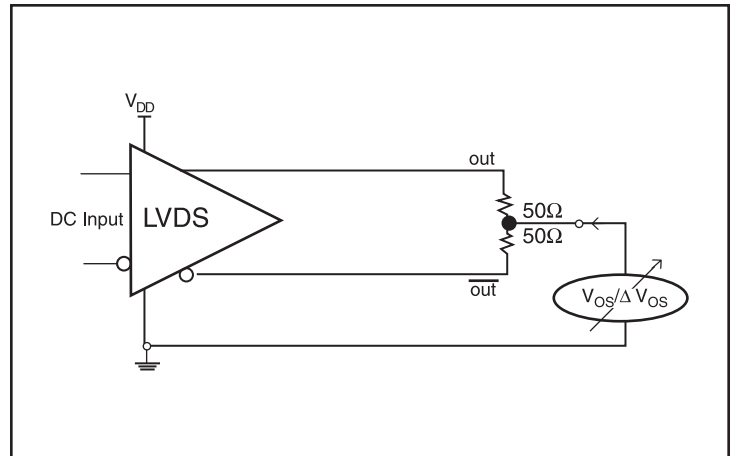
Output Rise/Fall Time



Start-Up



Differential Output Voltage Setup



Offset Voltage Setup

## Applications Information

### Recommendations for Unused Input Pins

#### Inputs:

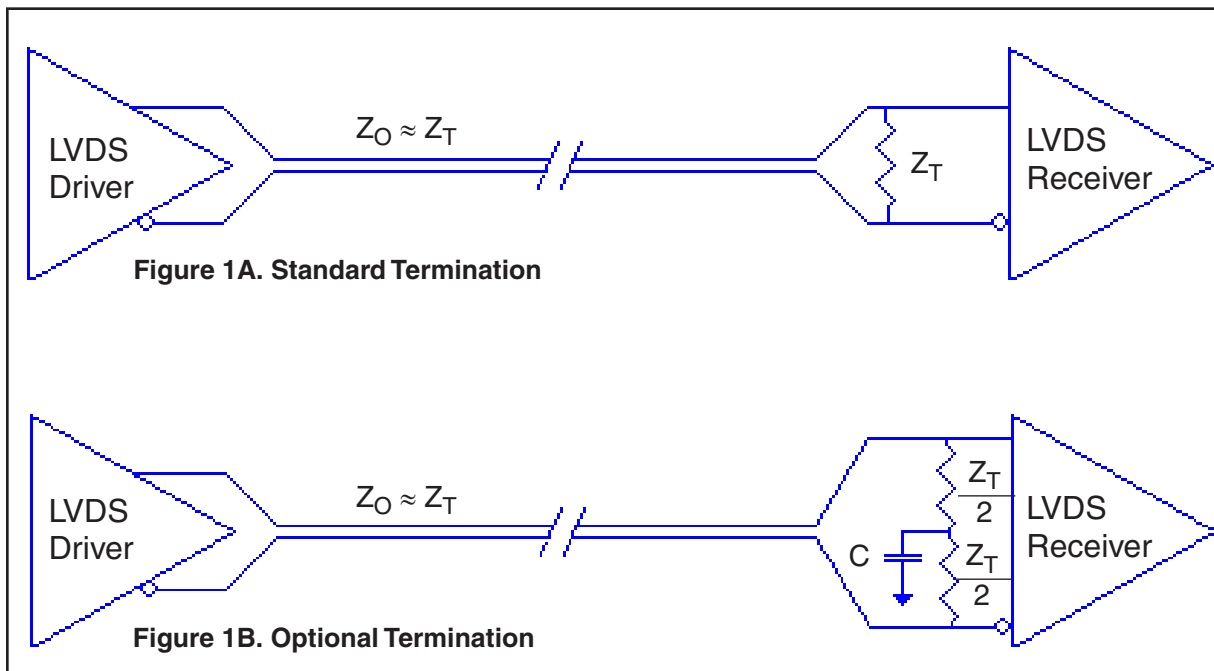
##### LVCMOS Select Pins

All control pins have internal pulldowns; additional resistance is not required but can be added for additional protection. A 1k $\Omega$  resistor can be used.

### LVDS Driver Termination

For a general LVDS interface, the recommended value for the termination impedance ( $Z_T$ ) is between 90 $\Omega$  and 132 $\Omega$ . The actual value should be selected to match the differential impedance ( $Z_0$ ) of your transmission line. A typical point-to-point LVDS design uses a 100 $\Omega$  parallel resistor at the receiver and a 100 $\Omega$  differential transmission-line environment. In order to avoid any transmission-line reflection issues, the components should be surface mounted and must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The

standard termination schematic as shown in *Figure 1A* can be used with either type of output structure. *Figure 1B*, which can also be used with both output types, is an optional termination with center tap capacitance to help filter common mode noise. The capacitor value should be approximately 50pF. If using a non-standard termination, it is recommended to contact IDT and confirm if the output structure is current source or voltage source type. In addition, since these outputs are LVDS compatible, the input receiver's amplitude and common-mode input range should be verified for compatibility with the output.



### LVDS Termination

## Power Considerations

This section provides information on power dissipation and junction temperature for the IDT8N4QV01. Equations and example calculations are also provided.

### 1. Power Dissipation.

The total power dissipation for the IDT8N4QV01 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

- Power (core)<sub>MAX</sub> =  $V_{DD\_MAX} * I_{DD\_MAX} = 3.465V * 160mA = 554.4mW$

### 2. Junction Temperature.

Junction temperature,  $T_j$ , is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature,  $T_j$ , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for  $T_j$  is as follows:  $T_j = \theta_{JA} * Pd\_total + T_A$

$T_j$  = Junction Temperature

$\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

$Pd\_total$  = Total Device Power Dissipation (example calculation is in section 1 above)

$T_A$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 49.4°C/W per Table 7 below.

Therefore,  $T_j$  for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.554\text{W} * 49.4^\circ\text{C/W} = 112.4^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example.  $T_j$  will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

**Table 7. Thermal Resistance  $\theta_{JA}$  for 10 Lead Ceramic 5mm x 7mm Package, Forced Convection**

$\theta_{JA}$ by Velocity			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	49.4°C/W	44.2°C/W	41°C/W

## Reliability Information

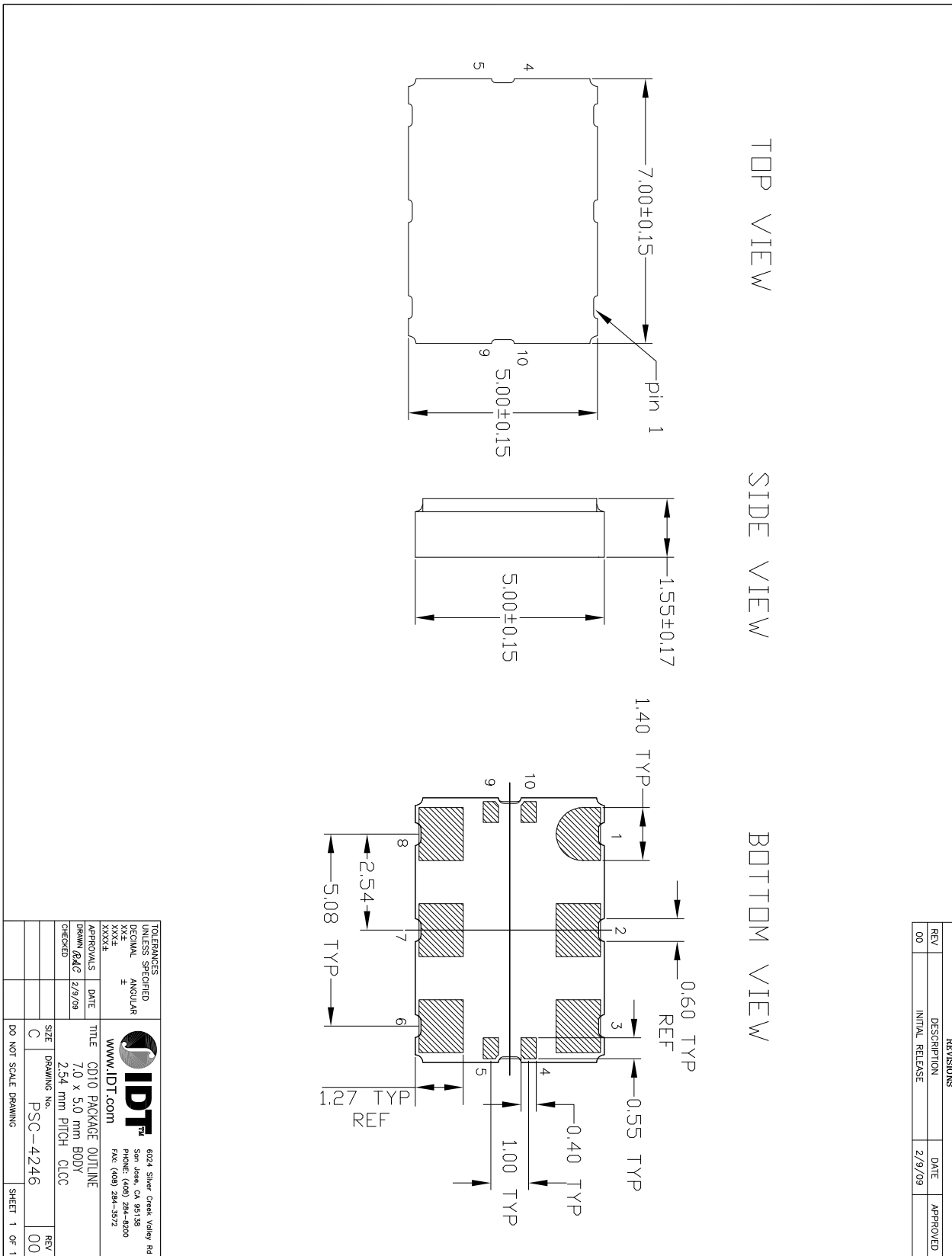
**Table 8.  $\theta_{JA}$  vs. Air Flow Table for a 10-lead Ceramic 5mm x 7mm Package**

$\theta_{JA}$ vs. Air Flow			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	49.4°C/W	44.2°C/W	41°C/W

## Transistor Count

The transistor count for IDT8N4QV01 is: 47,372

# Package Outline and Package Dimensions



REVISIONS			
REV	DESCRIPTION	DATE	APPROVED
00	INITIAL RELEASE	2/9/09	

TOLERANCES UNLESS SPECIFIED		 6024 Silver Creek Valley Rd San Jose, CA 95138 PHONE: (408) 284-8200 FAX: (408) 284-3572 WWW.IDT.COM
DECIMAL	ANGULAR	
XXXX	E	
XXXXX		
APPROVALS	DATE	TITLE
DRAWN: GAC	2/9/09	CD10 PACKAGE OUTLINE
CHECKED		7.0 x 5.0 mm BODY
		2.54 mm PITCH
		CLCC

SIZE	DRAWING No.	REV
C	PSC-4246	00
DO NOT SCALE DRAWING		SHEET 1 OF 1

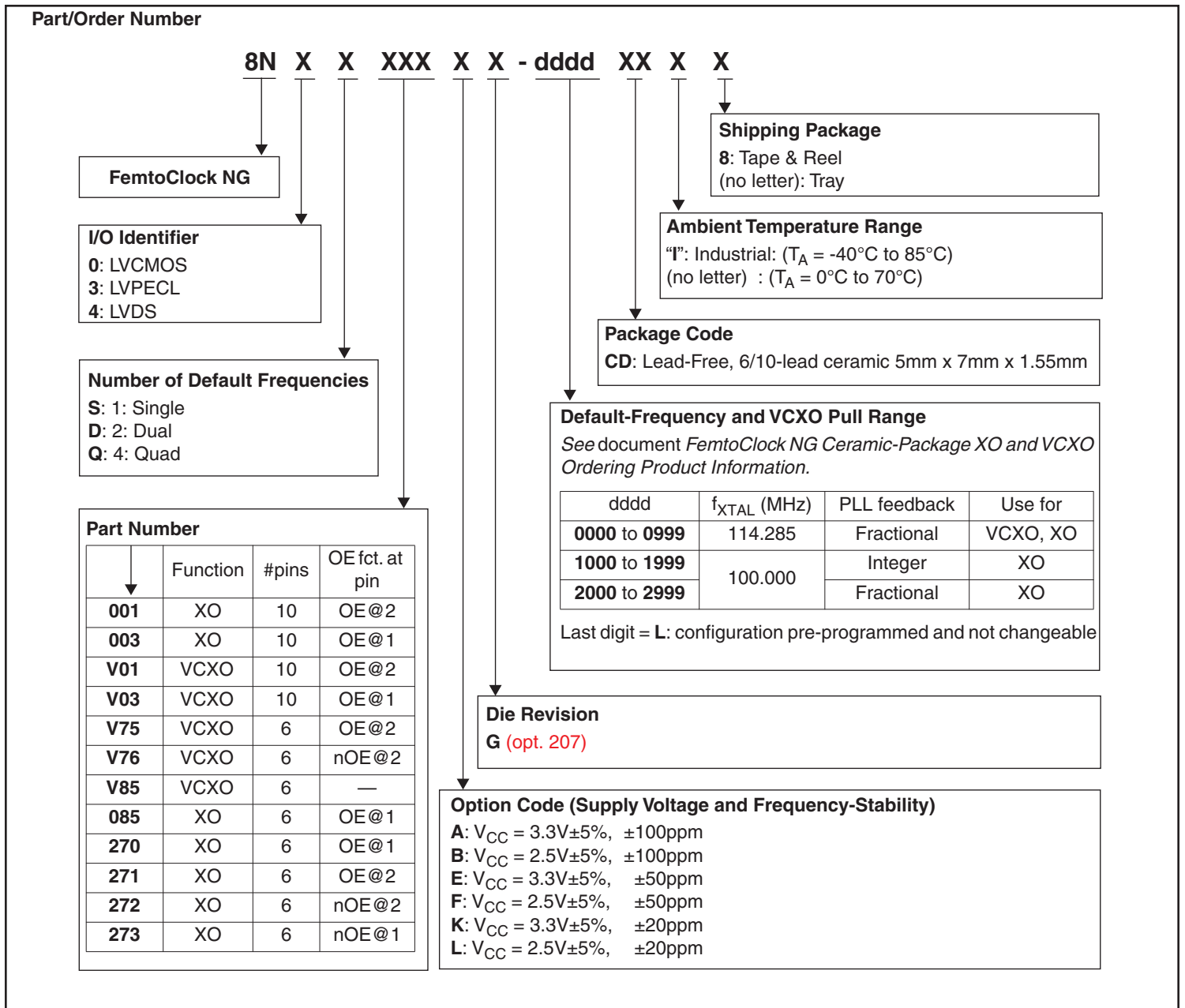


## Ordering Information for FemtoClock NG Ceramic-Package XO and VCXO Products

The programmable VCXO and XO devices support a variety of device options such as the output type, number of default frequencies, internal crystal frequency, power supply voltage, ambient temperature range and the frequency accuracy. The device options, default frequencies and default VCXO pull range must be specified at the time of order and are programmed by IDT before the shipment. The table below specifies the available order codes, including the device options and default frequency configurations. Example part number: the order code 8N3QV01FG-0001CDI specifies a programmable, quad default-frequency VCXO with a voltage supply of 2.5V, a LVPECL output, a  $\pm 50$  ppm crystal frequency accuracy,

contains a 114.285MHz internal crystal as frequency source, industrial temperature range, a lead-free (6/6 RoHS) 10-lead ceramic 5mm x 7mm x 1.55mm package and is factory-programmed to the default frequencies of 100, 122.88, 125 and 156.25MHz and to the VCXO pull range of min.  $\pm 100$  ppm.

Other default frequencies and order codes are available from IDT on request. For more information on available default frequencies, see the *FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information* document.



**Table 9. Device Marking**

Marking	Industrial Temperature Range ( $T_A = -40^\circ\text{C}$ to $85^\circ\text{C}$ )	Commercial Temperature Range ( $T_A = 0^\circ\text{C}$ to $70^\circ\text{C}$ )
		IDT8N4 <b>x</b> V01 <b>y</b> G- <b>dddd</b> CDI
<b>x</b> = Number of Default Frequencies, <b>y</b> = Option Code, <b>dddd</b> =Default-Frequency and VCXO Pull Range		

## Revision History Sheet

Rev	Table	Page	Description of Change	Date
A	T9	18	Table 9 Device Marking, corrected marking.	3/6/12
A	T1 T6A	2 8	Deleted "(see table 3C)" from the first table row, description column. NOTE 2; Deleted "from table 3C".	3/13/14

## We've Got Your Timing Solution



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